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<b>Form PTO-1449 Modified</b> <b>List of Patents and Publications</b> <b>Cited by Applicant</b> (Use several sheets if necessary) <b>U.S. Patent Department of Commerce</b> <b>Patent and Trademark Office</b>	<b>Docket No.:</b> 34646-00436USPX	<b>Serial No.:</b> Not Assigned
	<b>Applicants:</b> HALL, et al	
	<b>Filing Date:</b> Herewith	<b>Group:</b> Not Assigned

**U.S. PATENT DOCUMENTS**

Examiner Initials		Document No.	Date	Name	Class	Subclass
<i>AW</i>	AA	5,572,528	Nov. 5, 1996	Shuen	370	85.13
<i>AW</i>	AB	5,159,592	Oct. 27, 1992	Perkins	370	85.7
<i>AW</i>	AC	5,166,931	Nov. 24, 1992	Riddle	370	94.1
<i>AW</i>	AD	5,461,627	Oct. 24, 1995	Rypinski	370	95.2
<i>AW</i>	AE	5,708,655	Jan. 13, 1998	Toth et al.	370	313

<b>EXAMINER:</b>	<b>DATE CONSIDERED:</b>
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**FOREIGN PATENT DOCUMENTS**

Examiner Initials		Document No.	Date	Country	Translation	
					Yes	No
<i>AW</i>	AF	10032610 A	Feb. 3, 1998	Japan	X	
<i>AW</i>	AG	09098190 A	Apr. 8, 1997	Japan	X	
<i>AW</i>	AH	WO 97/48210	Dec. 18, 1997	PCT	X	
<i>AW</i>	AI	WO 95/27942	Oct. 19, 1995	PCT	X	
<i>AW</i>	AJ	WO 97/02734	Jan. 30, 1997	PCT	X	
<i>AW</i>	AK	WO 97/40610	Oct. 30, 1997	PCT	X	

<b>EXAMINER:</b>	<b>DATE CONSIDERED:</b>
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**OTHER REFERENCES**

Examiner Initials	Document Description
AL	Hansson, S.; International-Type Search Report; May 12, 1999; Search Request No. SE 98/00685; pp. 1-4.

<b>EXAMINER:</b> <i>AW</i>	<b>DATE CONSIDERED:</b> 8/10/92
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